

N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV _{DSS} /	R _{DS(ON)}	I _{D(ON)}	V _{GS(th)}	Order Number / Package
BV _{DGS}	(max) 1.5Ω	(min) 3.0A	(max) 2.0V	TO-92 TN0606N3
100V	1.5Ω	3.0A	2.0V	TN0610N3

Features

- Low threshold 2.0V max.
- High input impedance
- ☐ Low input capacitance 100pF typical
- Fast switching speeds
- Low on resistance
- ☐ Free from secondary breakdown
- Low input and output leakage
- Complementary N- and P-channel devices

Applications

- ☐ Logic level interfaces ideal for TTL and CMOS
- Solid state relays
- Battery operated systems
- Photo voltaic drives
- Analog switches
- General purpose line drivers
- □ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}		
Drain-to-Gate Voltage	BV_{DGS}		
Gate-to-Source Voltage	± 20V		
Operating and Storage Temperature	-55°C to +150°C		
Soldering Temperature*	300°C		

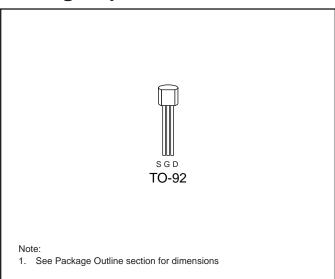
^{*} Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Option



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Thermal Characteristics

Package	I _D (continuous)*	I _D (pulsed)	Power Dissipation @ T _C = 25°C	$^{ heta_{ extsf{jc}}}$ $^{\circ}$ C/W	$ heta_{ja}$ °C/W	I _{DR} *	I _{DRM}
TO-92	0.5A	3.2A	1W	125	170	0.5A	3.2A

^{*} I_D (continuous) is limited by max rated T_i.

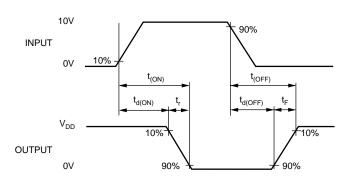
Electrical Characteristics (@ 25°C unless otherwise specified)

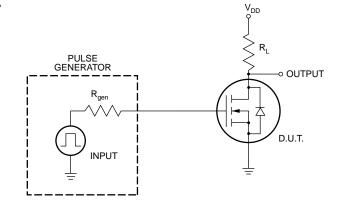
Symbol	ymbol Parameter		Min	Тур	Max	Unit	Conditions	
BV _{DSS}	Drain-to-Source	TN0610	100			V	$V_{GS} = 0V$, $I_D = 1mA$	
	Breakdown Voltage	TN0606	60					
V _{GS(th)}	Gate Threshold Voltage		0.6		2.0	V	$V_{GS} = V_{DS}, I_D = 1mA$	
$\Delta V_{GS(th)}$	Change in V _{GS(th)} with Temperature				-4.5	mV/°C	$V_{GS} = V_{DS}$, $I_D = 1mA$	
I _{GSS}	Gate Body Leakage				100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
I _{DSS}	Zero Gate Voltage Drain Current				10	μΑ	V _{GS} = 0V, V _{DS} = Max Rating	
				1.0	mA	$V_{GS} = 0V$, $V_{DS} = 0.8$ Max Rating $T_A = 125^{\circ}C$ (note 2)		
I _{D(ON)}	ON-State Drain Current		1.2	2.0		А	$V_{GS} = 5V, V_{DS} = 25V$	
	†			6.7		-	$V_{GS} = 10V, V_{DS} = 25V$	
					15	Ω	$V_{GS} = 3V, I_D = 0.25A$	
$R_{DS(ON)}$	Static Drain-to-Source	tic Drain-to-Source		1.5	2.0		$V_{GS} = 5V, I_D = 0.75A$	
	ON-State Resistance			1.0	1.5		$V_{GS} = 10V, I_D = 0.75A$	
$\Delta R_{DS(ON)}$	N) Change in R _{DS(ON)} with Temperature				0.75	%/°C	$V_{GS} = 10V, I_D = 0.75A$	
G _{FS}	Forward Transconductance		0.4	0.5		$^{\circ}$	$V_{DS} = 25V, I_{D} = 1.0A$	
C _{ISS}	Input Capacitance		100	150	pF	$V_{GS} = 0V, V_{DS} = 25V$		
C _{OSS}	Common Source Output Capa		50	85		f = 1 MHz		
C _{RSS}	Reverse Transfer Capacitance			10	35			
t _{d(ON)}	Rise Time				6	ns	V _{DD} = 25V	
t _r					14			
t _{d(OFF)}					16		$I_D = 1.5A$ $R_{GEN} = 25\Omega$	
t _f					16		GEN	
V _{SD}	Diode Forward Voltage Drop			0.8	1.8	V	$V_{GS} = 0V, I_{SD} = 1.5A$	
t _{rr}	Reverse Recovery Time			300		ns	V _{GS} = 0V, I _{SD} = 1.5A	

Notes:

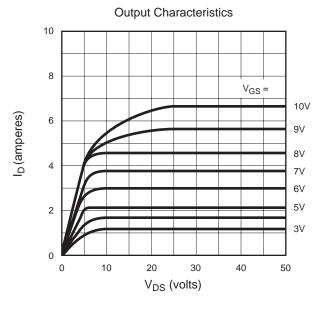
- 1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: $300\mu s$ pulse, 2% duty cycle.)
- 2. All A.C. parameters sample tested.

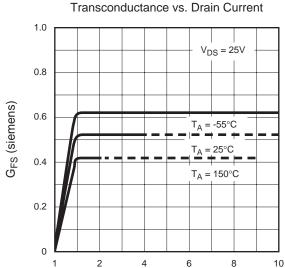
Switching Waveforms and Test Circuit



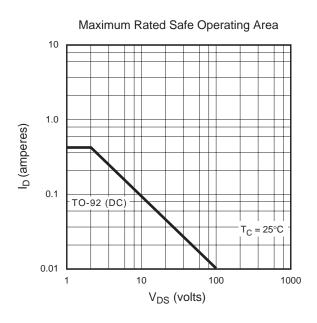


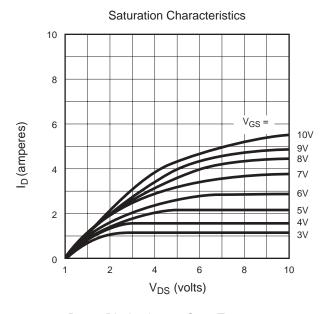
Typical Performance Curves

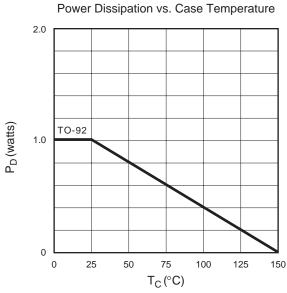


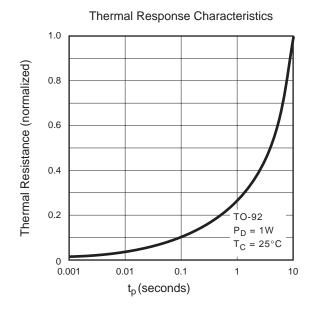


I_D (amperes)

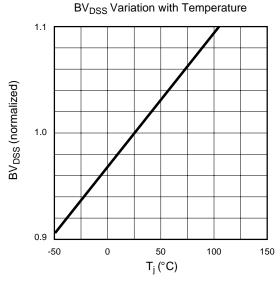


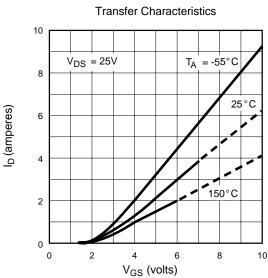


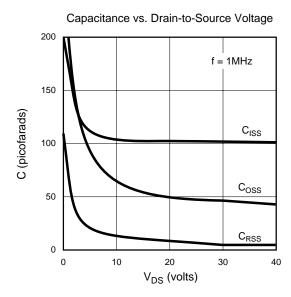


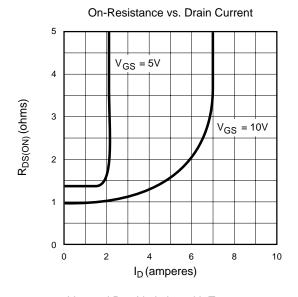


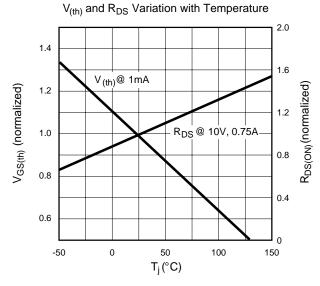
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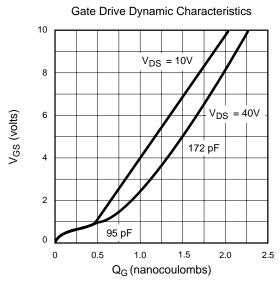












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